

TRANSMITTAL OF INFORMATION DISCLOSURE STATEMENT
(Under 37 CFR 1.97(b) or 1.97(c))

Docket No.
03850.010001

In Re Application Of: **Oliver KIENZLE, et al.**

Serial No.
09/934,262

Filing Date
08/21/2001

Examiner
MOHAMEDULLA, S.

Group Art Unit
1756

Title: **APPARATUS AND METHOD FOR EXPOSING A RADIATION SENSITIVE LAYER BY MEANS
OF CHARGED PARTICLES AS WELL AS A MASK FOR THIS PURPOSE**

Address to:
Assistant Commissioner for Patents
Washington, D.C. 20231

37 CFR 1.97(b)

1. ☒ The Information Disclosure Statement submitted herewith is being filed within three months of the filing of a national application; within three months of the date of entry of the national stage as set forth in 37 CFR 1.491 in an international application; or before the mailing date of a first Office Action on the merits, whichever event occurs last.

37 CFR 1.97(c)

2. ☐ The Information Disclosure Statement submitted herewith is being filed after three months of the filing of a national application, or the date of entry of the national stage as set forth in 37 CFR 1.491 in an international application; or after the mailing date of a first Office Action on the merits, whichever occurred last but before the mailing date of either:

1. a Final Action under 37 CFR 1.113, or
2. a Notice of Allowance under 37 CFR 1.311,

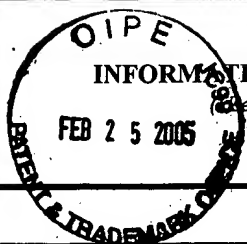
whichever occurs first.

Also submitted herewith is:

- ☐ a certification as specified in 37 CFR 1.97(e);

OR

- ☐ the fee set forth in 37 CFR 1.17(p) for submission of an Information Disclosure Statement under 37 CFR 1.97(c).



INFORMATION DISCLOSURE CITATION

(See several sheets if necessary)

Docket Number (Optional):

03850.0

01

Application Number

09/934,262

Applicant(s)

Oliver KIENZLE, et al.

Filing Date

08/21/2001

Group Art Unit

1756

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	A1	5,079,112	01/07/1992	Berger et al.	430	4	08/07/1989
	A2	5,130,213	07/14/1992	Berger et al.	430	4	03/23/1990
	A3	5,258,246	11/02/1993	Berger et al.	430	4	07/14/1992
	A4	5,260,151	11/09/1993	Berger et al.	430	5	12/30/1991
	A5	5,316,879	05/31/1994	Berger et al.	430	5	07/14/1992
	A6	5,376,505	12/27/1994	Berger et al.	430	296	03/16/1992
	A7	5,650,629	07/22/1997	Levi	250	491.1	06/28/1994
	A8	5,906,902	05/25/1999	Farrow	430	30	02/26/1997
	A9	5,985,493	11/16/1999	Liddle et al.	430	5	04/08/1998

FOREIGN PATENT DOCUMENTS

	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
							YES	NO
	A10	EP 0 953 876 A2	11/03/1999	Europe	G03F	1/14		
	A11	EP 0 969 326 A2	01/05/2000	Europe	G03F	7/20		

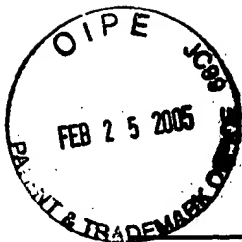
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.).

	A12	J. A Liddle, et al.; "SCALPEL: A Projection Electron-Beam Approach To Sub-Optical Lithography"; 71 pages; Technology Review, December 1999

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



PTO/SB/08a/b (08-03)

Approved for use through 07/31/2006. OMB 0651-0031

U.S. Patent and Trademark Office; U.S. DEPARTMENT OF COMMERCE

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Substitute for form 1449A/B/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use as many sheets as necessary)				Complete if Known	
				Application Number	09/934,262-Conf. #6459
				Filing Date	August 21, 2001
				First Named Inventor	Oliver Kienzle
				Art Unit	2881
				Examiner Name	K. T. Nguyen
Sheet	1	of	1	Attorney Docket Number	03850/010001

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number-Kind Code ² (if known)			

FOREIGN PATENT DOCUMENTS						
Examiner Initials*	Cite No. ¹	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ³
		Country Code ³ -Number ⁴ -Kind Code ⁵ (if known)				

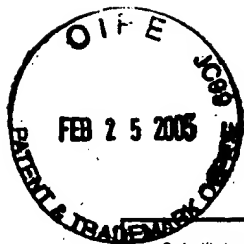
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NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
	A1	ESRF Annual Report for 1995/1996 located at http://www.esrf.fr/info/science/annrep/95-96/report/exp/id32/id32.htm , 9 pgs	

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¹ Applicant's unique citation designation number (optional). ² Applicant is to place a check mark here if English language Translation is attached.

Examiner Signature		Date Considered	
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Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
	A1	Patent Abstracts of Japan, Publication No. 11142121, Publication Date 05/28/1999, 1 page	
	A2	European Search Report dated December 16, 2003 (2 pages)	
	A3	R.C. Farrow et al.; "Marks for Alignment and Registration in Projection Electron Lithography"; Journal of Vacuum Science & Technology B; Vol. 11, No. 6, Nov/Dec 1993; pp. 2175-2178	

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